

ABSTRACT OF THE DISCLOSURE

An output voltage of a VDC circuit is subjected to A/D conversion with an on-chip A/D converter. Accordingly, an output voltage VDCout of the VDC circuit can be observed as a digital value, which facilitates measurement. Reduction in the number of terminals leads to reduction in chip size. In addition, the terminal that has been used for providing voltage VDCout can be used for other purposes. Therefore, a semiconductor integrated circuit allowing for easy mass production test and reduced number of man-hours in the mass production test can be provided.